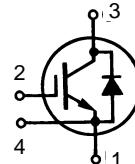


High Voltage IGBT with Diode

IXSN 35N120AU1

V_{CES} = 1200 V
 I_{C25} = 70 A
 $V_{CE(sat)}$ = 4 V

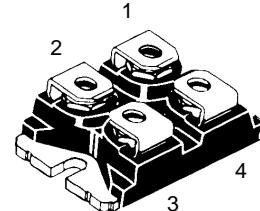


Symbol	Test Conditions	Maximum Ratings		
V_{CES}	$T_J = 25^\circ\text{C}$ to 150°C	1200	V	
V_{CGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GE} = 1 \text{ M}\Omega$	1200	A	
V_{GES}	Continuous	± 20	V	
V_{GEM}	Transient	± 30	V	
I_{C25}	$T_c = 25^\circ\text{C}$	70	A	
I_{C90}	$T_c = 90^\circ\text{C}$	35	A	
I_{CM}	$T_c = 25^\circ\text{C}$, 1 ms	140	A	
SSOA (RBSOA)	$V_{GE} = 15 \text{ V}$, $T_{VJ} = 125^\circ\text{C}$, $R_G = 22 \Omega$ Clamped inductive load, $L = 30 \mu\text{H}$	$I_{CM} = 70$ @ 0.8 V_{CES}	A	
t_{sc} (SCSOA)	$V_{GE} = 15 \text{ V}$, $V_{CE} = 0.6 \cdot V_{CES}$, $T_J = 125^\circ\text{C}$ $R_G = 22 \Omega$, non repetitive	10	μs	
P_c P_d	$T_c = 25^\circ\text{C}$	300	W	
P_d	Diode	175	W	
V_{ISOL}	50/60 Hz	t = 1 min	2500	V~
	$I_{ISOL} \leq 1 \text{ mA}$	t = 1 s	3000	V~
T_J		-55 ... +150	$^\circ\text{C}$	
T_{JM}		150	$^\circ\text{C}$	
T_{stg}		-55 ... +150	$^\circ\text{C}$	
M_d	Mounting torque	1.5/13	Nm/lb.in.	
	Terminal connection torque (M4)	1.5/13	Nm/lb.in.	
Weight		30	g	

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
BV_{CES}	$I_c = 5 \text{ mA}$, $V_{GE} = 0 \text{ V}$	1200		V
$V_{GE(th)}$	$I_c = 4 \text{ mA}$, $V_{CE} = V_{GE}$	4		V
I_{CES}^{\circledast}	$V_{CE} = 0.8 \cdot V_{CES}$ $V_{GE} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		$750 \mu\text{A}$ 15 mA
I_{GES}	$V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$			$\pm 100 \text{ nA}$
$V_{CE(sat)}$	$I_c = I_{C90}$, $V_{GE} = 15 \text{ V}$		4	V

② Device must be heat sunk during high temperature leakage test to avoid thermal runaway.

miniBLOC, SOT-227 B



1 = Emitter ①, 3 = Collector
 2 = Gate, 4 = Emitter ①

① Either Emitter terminal can be used as Main or Kelvin Emitter

Features

- International standard package miniBLOC (ISOTOP) compatible
- Aluminium-nitride isolation
 - high power dissipation
- Isolation voltage 3000 V~
- Low $V_{CE(sat)}$
 - for minimum on-state conduction losses
- Fast Recovery Epitaxial Diode
 - short t_{rr} and I_{RM}
- Low collector-to-case capacitance (< 50 pF)
 - reducesd RFI
- Low package inductance (< 10 nH)
 - easy to drive and to protect

Applications

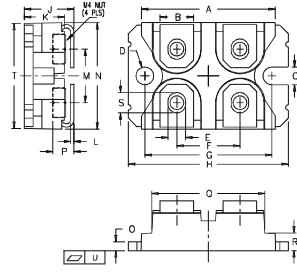
- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switch-mode and resonant-mode power supplies

Advantages

- Space savings
- Easy to mount with 2 screws
- High power density

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
g_{fs}	$I_C = I_{C90}$; $V_{CE} = 10 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2\%$	20	26	S
$I_{C(on)}$	$V_{CE} = 10 \text{ V}$, $V_{GE} = 15 \text{ V}$		170	A
C_{ies}	$V_{CE} = 25 \text{ V}$, $V_{GE} = 0 \text{ V}$, $f = 1 \text{ MHz}$	3900		pF
C_{oes}		295		pF
C_{res}		60		pF
Q_g	$I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$, $V_{CE} = 0.5 V_{CES}$	150	190	nC
Q_{ge}		40	60	nC
Q_{gc}		70	100	nC
$t_{d(on)}$	Inductive load, $T_J = 25^\circ\text{C}$ $I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$, $V_{CE} = 0.8 \cdot V_{CES}$, $R_G = 2.7 \Omega$ Remarks: Switching times may increase for V_{CE} (Clamp) > $0.8 \cdot V_{CES}$, higher T_J or increased R_G	80		ns
t_{ri}		150		ns
$t_{d(off)}$		400	900	ns
t_{fi}		500	700	ns
E_{off}		10		mJ
$t_{d(on)}$	Inductive load, $T_J = 125^\circ\text{C}$ $I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$, $V_{CE} = 0.8 \cdot V_{CES}$, $R_G = 2.7 \Omega$ Remarks: Switching times may increase for V_{CE} (Clamp) > $0.8 \cdot V_{CES}$, higher T_J or increased R_G	80		ns
t_{ri}		150		ns
$t_{d(off)}$		400		ns
t_{fi}		700		ns
E_{on}		6		mJ
E_{off}		15		mJ
R_{thJC}			0.42	K/W
R_{thCK}		0.05		K/W

miniBLOC, SOT-227 B



M4 screws (4x) supplied

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

Reverse Diode (FRED)

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_F	$I_F = I_{C90}$, $V_{GE} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2\%$		2.35	V
I_{RM}	$I_F = I_{C90}$, $V_{GE} = 0 \text{ V}$, $-di_F/dt = 480 \text{ A}/\mu\text{s}$ $V_R = 540 \text{ V}$ $T_J = 100^\circ\text{C}$ $I_F = 1 \text{ A}$; $-di/dt = 200 \text{ A}/\mu\text{s}$; $V_R = 30 \text{ V}$ $T_J = 25^\circ\text{C}$	32	35	A
t_{rr}		225	ns	
		40	60	ns
R_{thJC}			0.71	K/W

Fig. 1 Saturation Characteristics

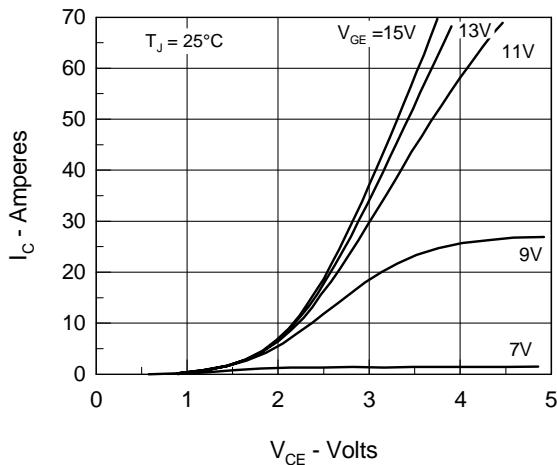


Fig. 3 Collector-Emitter Voltage vs. Gate-Emitter Voltage

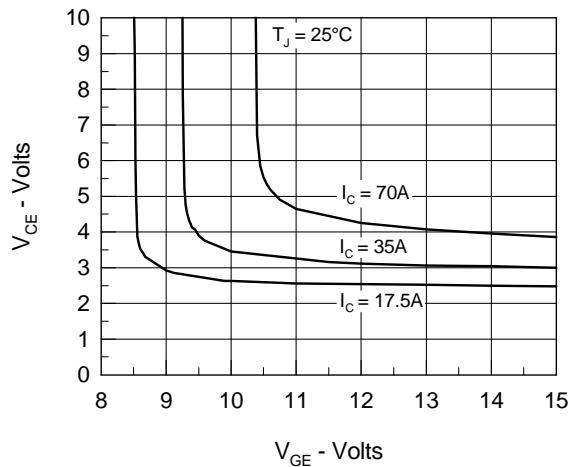


Fig. 5 Input Admittance

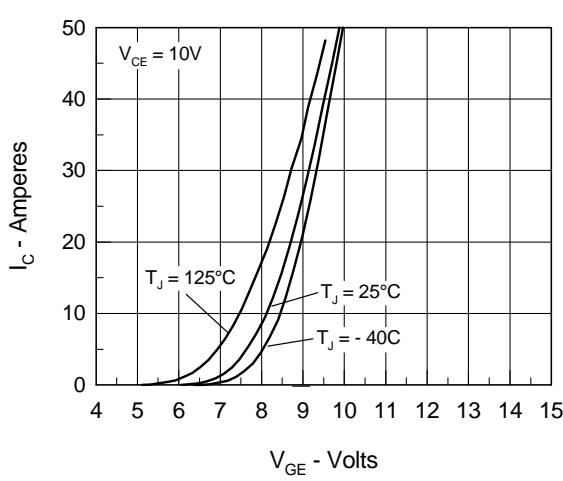


Fig. 2 Output Characteristics

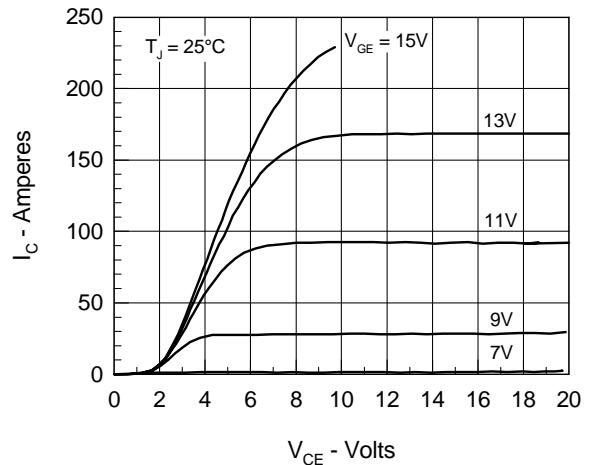


Fig. 4 Temperature Dependence of Output Saturation Voltage

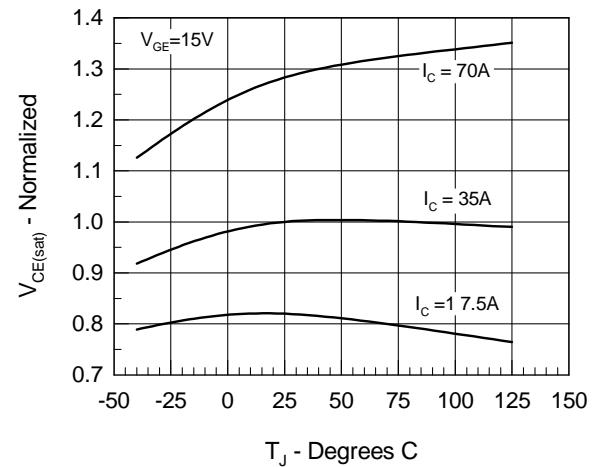


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage

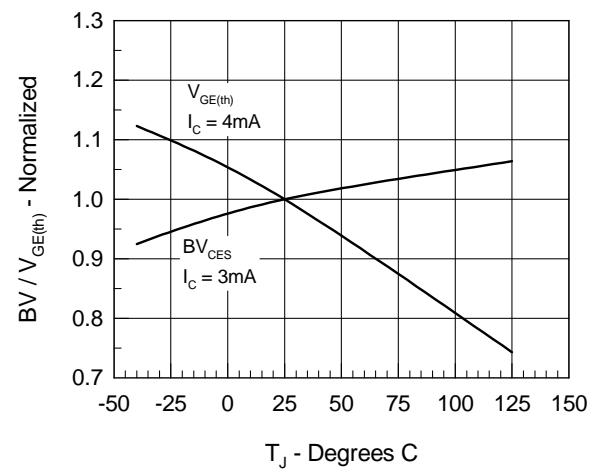


Fig.7 Turn-Off Energy per Pulse and Fall Time on Collector Current

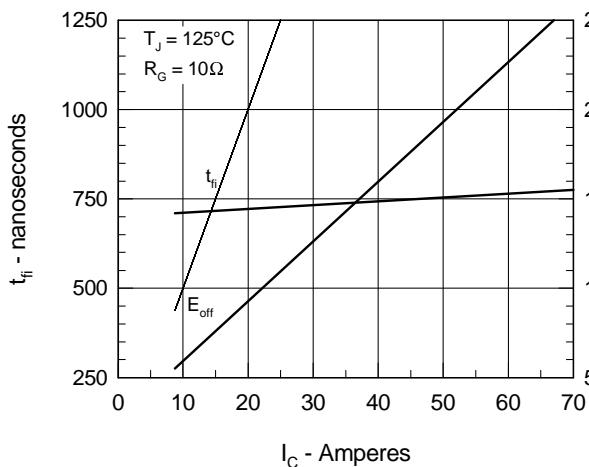


Fig.8 Dependence of Turn-Off Energy Per Pulse and Fall Time on R_G

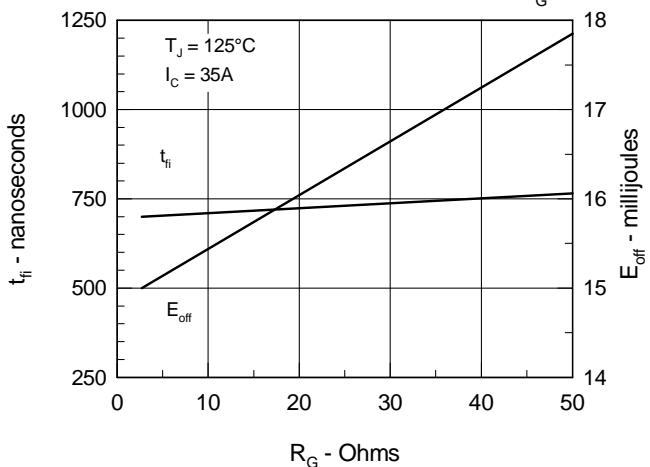


Fig.9 Gate Charge Characteristic Curve

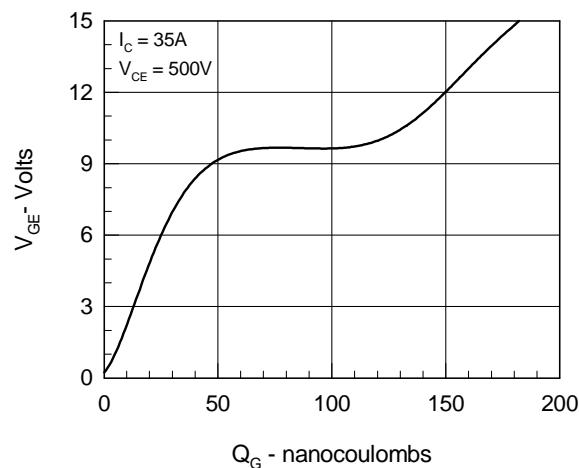


Fig.10 Turn-Off Safe Operating Area

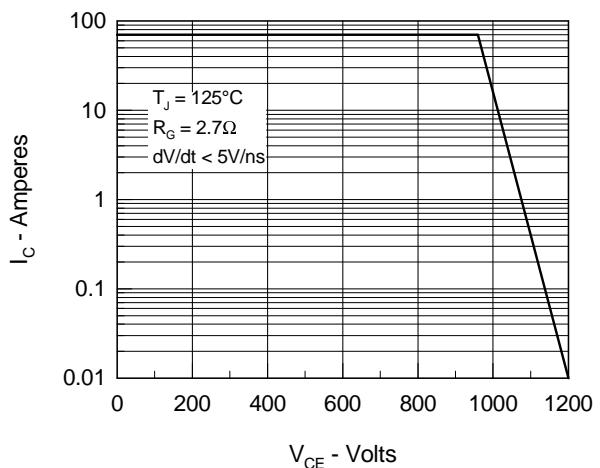


Fig.11 Transient Thermal Impedance

